

July 2006

FDFMA2P853

Integrated P-Channel PowerTrench® MOSFET and Schottky Diode

General Description

This device is designed specifically as a single package solution for the battery charge switch in cellular handset and other ultra-portable applications. It features a MOSFET with low on-state resistance and an independently connected low forward voltage schottky diode for minimum conduction losses.

The MicroFET 2x2 package offers exceptional thermal performance for it's physical size and is well suited to linear mode applications.



Features MOSFET:

■ -3.0 A, -20V. $R_{DS(ON)} = 120 \text{ m}\Omega$ @ $V_{GS} = -4.5 \text{ V}$

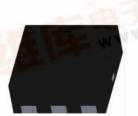
 $R_{DS(ON)}$ = 160 m Ω @ V_{GS} = -2.5 V

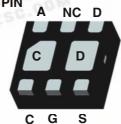
 $R_{DS(ON)} = 240 \text{ m}\Omega$ @ $V_{GS} = -1.8 \text{ V}$

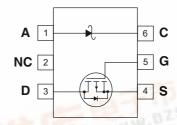
Schottky:

V_F < 0.46 V @ 500 mA

- Low Profile 0.8 mm maximun in the new package MicroFET 2x2 mm
- RoHS Compliant







MicroFET

Absolute Maximum Ratings TA = 25°C unless otherwise noted

Symbol	Parameter		Ratings	Units	
V _{DSS}	MOSFET Drain-Source Voltage	110	-20	V	
V_{GSS}	MOSFET Gate-Source Voltage	±8	V		
	Drain Current -Continuous	(Note 1a)	-2.2	Α	
ID	-Pulsed		-6	_ A	
V _{RRM}	Schottky Repetitive Peak Reverse voltage		30	V	
Io	Schottky Average Forward Current (Note 1a)		1	Α	
D	Power dissipation for Single Operation	(Note 1a)	1.4	W	
$ P_{D} $	Power dissipation for Single Operation	(Note 1b)	0.7	VV	
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C	

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	86	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1b)	173	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1c)	86	*C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1d)	140	

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape Width	Quantity
.853	FDFMA2P853	7inch	8mm	3000 units

Symbol	Parameter	Test Conditions		Min	Тур	Max	Units
Off Chara	acteristics			•			
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 V$, $I_D =$	–250 μΑ	-20			V
<u>ΔBV_{DSS}</u> ΔΤ _J	Breakdown Voltage Temperature Coefficient	$I_D = -250 \mu A$, Refe	renced to 25°C		-12		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -16 \text{ V}, V_{GS}$	= 0 V			-1	μА
I _{GSS}	Gate–Body Leakage	$V_{GS} = \pm 8 \text{ V}, V_{DS}$				±100	nA
On Chara	acteristics (Note 2)			•			
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} =$	–250 μΑ	-0.4	-0.7	-1.3	V
$\Delta V_{GS(th)} \over \Delta T_{,l}$	Gate Threshold Voltage Temperature Coefficient	$I_D = -250 \mu\text{A}, \text{Refe}$			2		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance	$V_{GS} = -4.5 \text{ V}, I_D = -3.0 \text{ A}$ $V_{GS} = -2.5 \text{ V}, I_D = -2.5 \text{ A}$ $V_{GS} = -1.8 \text{ V}, I_D = -1.0 \text{ A}$ $V_{GS} = -4.5 \text{ V}, I_D = -3.0 \text{ A}, T_J = 125 ^{\circ}\text{C}$			90 120 172 118	120 160 240 160	mΩ
I _{D(on)}	On–State Drain Current	$V_{GS} = -4.5 \text{ V}, V_{DS} = -5 \text{ V}$					Α
g _{FS}	Forward Transconductance	$V_{DS} = -5 \text{ V}, \qquad I_D =$	-3.0 A		7		S
Dvnamic	Characteristics						
C _{iss}	Input Capacitance	V _{DS} = -10 V, V _G	s = 0 V.		435		pF
C _{oss}	Output Capacitance	f = 1.0 MHz			80		pF
C _{rss}	Reverse Transfer Capacitance				45		pF
Switchin	g Characteristics (Note 2)	ı		I	1	1	
t _{d(on)}	Turn-On Delay Time	$V_{DD} = -10 \text{ V}, I_D = -1 \text{ A},$ $V_{GS} = -4.5 \text{ V}, R_{GEN} = 6 \Omega$ $V_{DS} = -10 \text{ V}, I_D = -3.0 \text{ A},$ $V_{GS} = -4.5 \text{ V}$			9	18	ns
t _r	Turn-On Rise Time				11	19	ns
$t_{d(off)}$	Turn-Off Delay Time				15	27	ns
t _f	Turn-Off Fall Time				6	12	ns
$\overline{Q_g}$	Total Gate Charge				4	6	nC
Q _{gs}	Gate–Source Charge				0.8		nC
$\overline{Q_{gd}}$	Gate-Drain Charge				0.9		nC
Drain-Sc	ource Diode Characteristics	and Maximum	Ratings				
Is	Maximum Continuous Drain-Source					-1.1	Α
V_{SD}	Drain–Source Diode Forward Voltage	$V_{GS} = 0 V$, $I_{S} =$	-1.1 A (Note 2)		-0.8	-1.2	V
t _{rr}	Diode Reverse Recovery Time	$I_F = -3.0 \text{ A},$			17		ns
Q _{rr}	Diode Reverse Recovery Charge	dl _F /dt = 100 A/μs			6		nC
Schottky	Diode Characteristics						
I _R	Reverse Leakage	V _R = 5 V	T _J = 25°C T _J = 125°C		9.9 2.3	50 10	μA mA
I _R	Reverse Leakage	V _R = 20 V	T _J = 25°C		9.9	100	μА
			T _J = 85°C		0.3	1	mΑ
			T _J = 125°C		2.3	10	mA
V _F	Forward Voltage	I _F = 500mA	T _J = 25°C		0.4	0.46	V
			T _J = 125°C		0.3	0.35	
V _F	Forward Voltage	I _F = 1A	T _J = 25°C		0.5	0.55	V
			T _J = 125°C		0.49	0.54	

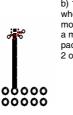
Electrical Characteristics T_A = 25°C unless otherwise noted

Notes:

- 1. $R_{\theta JA}$ is determined with the device mounted on a 1 in² oz. copper pad on a 1.5 x 1.5 in. board of FR-4 material. $R_{\theta JC}$ is guaranteed by design while $R_{\theta JA}$ is determined by the user's board design.
 - (a) MOSFET $R_{\theta JA}$ = 86°C/W when mounted on a 1 in² pad of 2 oz copper, 1.5" x 1.5" x 0.062" thick PCB
 - (b) MOSFET $R_{\theta JA}$ = 173°C/W when mounted on a minimum pad of 2 oz copper
 - (c) Schottky $R_{\theta JA} = 86^{\circ}$ C/W when mounted on a 1 in² pad of 2 oz copper, 1.5" x 1.5" x 0.062" thick PCB
 - (d) Schottky $R_{\theta,JA} = 140^{\circ}$ C/W when mounted on a minimum pad of 2 oz copper



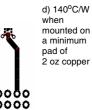
a) 86°C/W when mounted on a 1in² pad of 2 oz copper



b) 173°C/W when mounted on a minimum pad of 2 oz copper



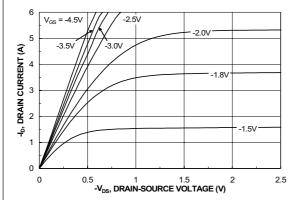
c) 86°C/W when mounted on a 1in² pad of 2 oz copper



Scale 1: 1 on letter size paper

2. Pulse Test: Pulse Width < $300\mu s$, Duty Cycle < 2.0%

Typical Characteristics



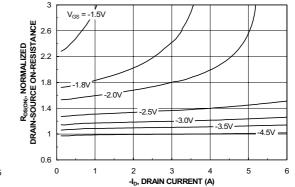
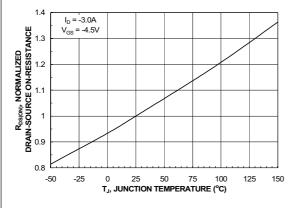


Figure 1. On-Region Characteristics

Figure 2. On-Resistance Variation with Drain Current and Gate Voltage



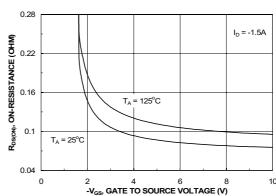
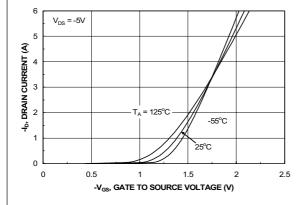


Figure 3. On-Resistance Variation with Temperature

Figure 4. On-Resistance Variation with Gate-to-Source Voltage



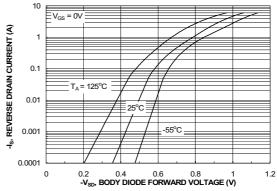


Figure 5. Transfer Characteristics

Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature

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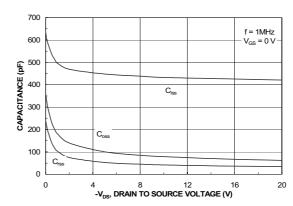
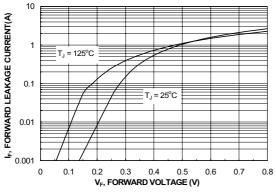


Figure 8. Capacitance Characteristics



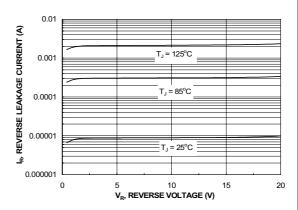


Figure 9. Schottky Diode Forward Voltage

Figure 10. Schottky Diode Reverse Current

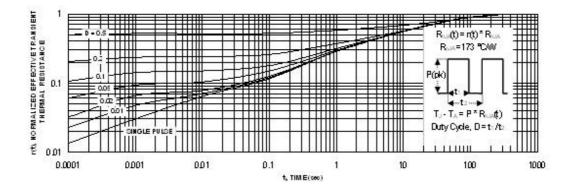
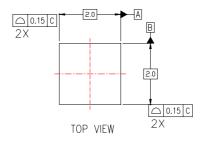
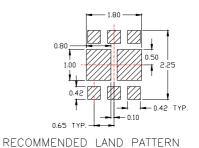
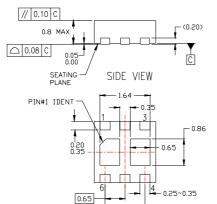


Figure 11. Transient Thermal Response Curve

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.







BOTTOM VIEW

1.30 0.1000 CAIB

NOTES:

- A. CONFORMS TO JEDEC REGISTRATION MO-229, VARIATION VCCC, DATED 11/2001
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994

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